

Notice of References Cited	Application/Control No. 10/092,887	Applicant(s)/Patent Under Reexamination BRANDES ET AL.	
	Examiner Scott R. Wilson	Art Unit 2826	Page 1 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-US005818071A	10-1998	Loboda et al.	257/77
	B	US-US005425860A	06-1995	Truher et al.	204/192.23
	C	US-4109271 A	08-1978	Pankove	257/53
	D	US-4451119 A	05-1984	Meyers et al.	359/846
	E	US-US005831324A	11-1998	Bang	257/508
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Gail Dewey, "Morton Announces Low Resistivity Components for Semiconductor Manufacturing", 18 June 1999, Rohm and Haas Co. Press Release and CVD Silicon Carbide Data Sheet.
	V	Nagai et al., "SiC Thin Film Thermistor", Thin Solid Films, Vol. 125, (October 11, 1984), pp. 355-359.
	W	Wahab et al., "Growth of epitaxial 3C-SiC films on (111) silicon substrates at 850 deg C by reactive magnetron sputtering", Journal of Applied Physics, Vol. 74, Issue 3, (August 1, 1993), pp. 1663-1669.
	X	Kortright et al., "Amorphous silicon carbide coatings for extreme ultraviolet optics", 15 July 1988, Applied Optics, Vol. 27, No. 14, pp. 2841-2846.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/092,887	Applicant(s)/Patent Under Reexamination BRANDES ET AL.	
	Examiner Scott R. Wilson	Art Unit 2826	Page 2 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Zappe et al., "High Temperature 10 Bar Pressure Sensor Based on 3C-SiC/SOI for Turbine Control Applications", Materials Science Forum, vol. 353-356, p. 753-756, 2001.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.